



ElectroMagnetic Field(EMF) Radiation Exposure TEST REPORT

No. I22Z62197-SEM01

For

HONOR Device Co., Ltd.

Smart Phone

Model Name: PGT-N19

with

Hardware Version: HN2PGETM

Software Version: 7.1.0.107(C900E100R1P2)

FCC ID: 2AYGCPGT-N19

Issued Date: 2023-3-5

Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of CTTL.

Test Laboratory:

CTTL, Telecommunication Technology Labs, CAICT

No. 52, Huayuan North Road, Haidian District, Beijing, P. R. China 100191.

Tel:+86(0)10-62304633-2512, Fax:+86(0)10-62304633-2504

Email: ctl_terminals@caict.ac.cn, website: www.caict.ac.cn



REPORT HISTORY

Report Number	Revision	Issue Date	Description
I22Z62197-SEM01	Rev.0	2023-2-1	Initial creation of test report
I22Z62197-SEM01	Rev.1	2023-3-5	Update the information on section 7



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1 Test Laboratory

1.1 Testing Location

Company Name:	CTTL
Address:	No. 52, Huayuan North Road, Haidian District, Beijing, P. R. China 100191.

1.2 Testing Environment

Temperature:	Min. = 18°C, Max. = 25°C
Relative humidity:	Min. = 30%, Max. = 70%
Ground system resistance:	< 0.5 Ω
Ambient noise & Reflection:	< 0.012 W/kg

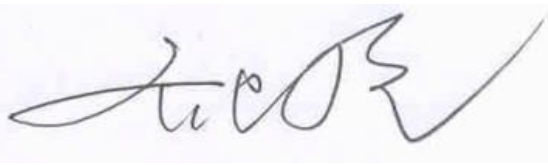
1.3 Project Data

Project Leader:	Qi Dianyuan
Test Engineer:	Lin Xiaojun
Testing Start Date:	January 19, 2023
Testing End Date:	January 19, 2023

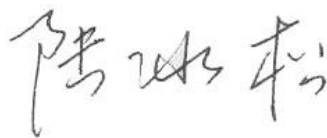
1.4 Signature



Lin Xiaojun
(Prepared this test report)



Qi Dianyuan
(Reviewed this test report)



Lu Bingsong
Deputy Director of the laboratory
(Approved this test report)



2 Statement of Compliance

According to 'KDB680106 D01 RF Exposure Wireless Charging App v03r01', for mobile WPT equipment, its H-field needs to be measured at 15 cm and is limited to 1.63A/m. the measured value at 14cm is <0.01.

3 Client Information

3.1 Applicant Information

Company Name:	HONOR Device Co., Ltd.
Address/Post:	Shum Yip Sky Park, No. 8089, Hongli West Road, Shenzhen, China
Contact Person:	/
Contact Email:	/
Telephone:	/
Fax	/

3.2 Manufacturer Information

Company Name:	HONOR Device Co., Ltd.
Address/Post:	Shum Yip Sky Park, No. 8089, Hongli West Road, Shenzhen, China
Contact Person:	/
Contact Email:	/
Telephone:	/
Fax	/

4 Equipment Under Test (EUT) and Ancillary Equipment (AE)

4.1 About EUT

Description:	Smart Phone
Model Name:	PGT-N19
Tested mode:	Wireless Charging
Operating Frequency:	110–148 kHz
Test device Production information:	Production unit
Device type:	Portable device
Antenna type:	Integrated antenna
Hotspot mode:	Support

4.2 Internal Identification of EUT used during the test

EUT ID*	IMEI	HW Version	SW Version
EUT1	866456060028237	HN2PGETM	7.1.0.107(C900E100R1P2)
EUT2	866456060024061	HN2PGETM	7.1.0.107(C900E100R1P2)

*EUT ID: is used to identify the test sample in the lab internally.

Note: It is performed to test E-field strength with the EUT1-2.

4.3 Internal Identification of AE used during the test

AE ID*	Description	Model	SN	Manufacturer
AE1	Battery	HB536880EHW	/	Honor Device Co., Ltd. (SCUD (FUJIAN Electronics Co., Ltd.))

*AE ID: is used to identify the test sample in the lab internally.

5 TEST METHODOLOGY

5.1 Applicable Measurement Standards

KDB 680106 D01 RF Exposure Wireless Charging Apps v03r01
TCB Workshop April 2022: Part 18 & Wireless Power Transfer

5.2 RF Exposure Requirements

For devices designed for typical desktop applications, such as wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 15 cm. E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 15 cm measured from the center of the probe(s) to the edge of the device. Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m. Below 100 kHz, applicable reference levels for maximum instantaneous exposure field strengths are defined in clause 3.a).(2).

Table 1 to § 1.1310(e)(1) - Limits for Maximum Permissible Exposure (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(i) Limits for Occupational/Controlled Exposure				
0.3-3.0	614	1.63	*(100)	≤6
3.0-30	1842/f	4.89/f	*(900/f ²)	<6
30-300	61.4	0.163	1.0	<6
300-1,500			f/300	<6
1,500-100,000			5	<6
(ii) Limits for General Population/Uncontrolled Exposure				
0.3-1.34	614	1.63	*(100)	<30
1.34-30	824/f	2.19/f	*(180/f ²)	<30
30-300	27.5	0.073	0.2	<30
300-1,500			f/1500	<30
1,500-100,000			1.0	<30

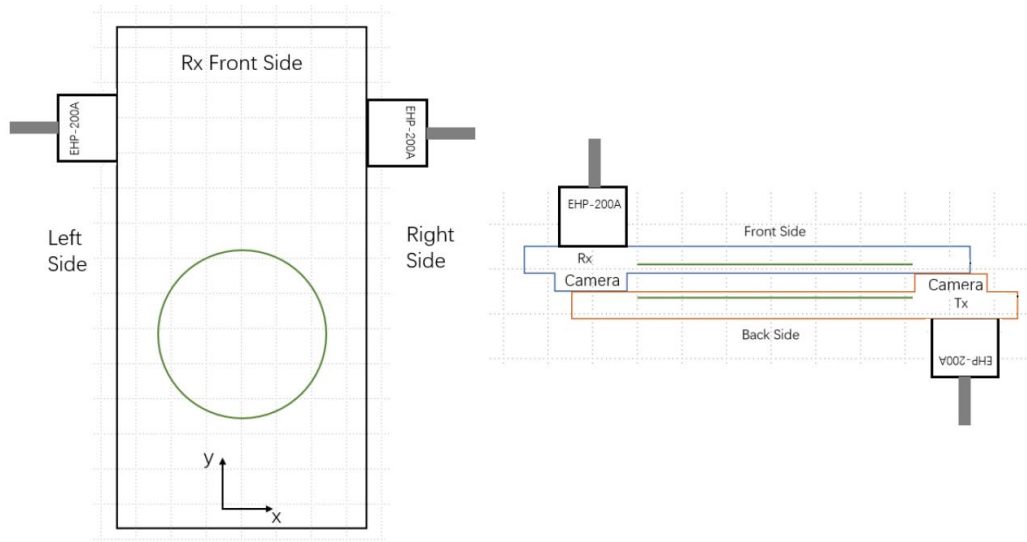
f = frequency in MHz. * = Plane-wave equivalent power density.

5.3 KDB 680106 D01 Equipment Approval Considerations

Requirement	Device
1. Power transfer frequency is less than 1MHz.	Yes. Operating Frequency is 110–148 kHz.
2. Output power from each primary coil is less than or equal to 15watts.	Yes. The maximum power is 7.5 Watts
3. The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.	Yes. The system includes one single primary and secondary coil and the device is designed to charge a single client.
4. Client device is placed directly in contact with the transmitter.	Yes. The client device is placed directly in contact with the transmitter.
5. Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion).	No. It is a portable device.
6. The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. less than 50%.

6 Test Setup

E- and H-field data are taken along all three axes the device, from 0 cm to 20 cm, in 2 cm minimum increment measured from the edge of the device, with one axis coincident with the axis of the main coil.



7 H-field strength Test Results

Position	Distance (cm)	Tx Power (W)	Freq (kHz)	H-field (A/m)
Front Side	0	5	112.8	2.198
Front Side	2	5	112.8	0.952
Front Side	4	5	112.8	0.561
Front Side	6	5	112.8	0.316
Front Side	8	5	112.8	0.211
Front Side	10	5	112.8	<0.01
Front Side	12	5	112.8	<0.01
Front Side	14	5	112.8	<0.01
Front Side	16	5	112.8	<0.01
Front Side	18	5	112.8	<0.01
Back Side	0	5	112.8	2.244
Back Side	2	5	112.8	0.969
Back Side	4	5	112.8	0.573
Back Side	6	5	112.8	0.332
Back Side	8	5	112.8	0.225
Back Side	10	5	112.8	<0.01
Back Side	12	5	112.8	<0.01
Back Side	14	5	112.8	<0.01
Back Side	16	5	112.8	<0.01
Back Side	18	5	112.8	<0.01
Right Side	0	5	112.8	2.551
Right Side	2	5	112.8	1.051
Right Side	4	5	112.8	0.338
Right Side	6	5	112.8	0.284
Right Side	8	5	112.8	0.230
Right Side	10	5	112.8	<0.01
Right Side	12	5	112.8	<0.01
Right Side	14	5	112.8	<0.01
Right Side	16	5	112.8	<0.01
Right Side	18	5	112.8	<0.01
Left Side	0	5	112.8	3.208
Left Side	2	5	112.8	1.240
Left Side	4	5	112.8	0.972
Left Side	6	5	112.8	0.462
Left Side	8	5	112.8	0.302
Left Side	10	5	112.8	0.223
Left Side	12	5	112.8	<0.01
Left Side	14	5	112.8	<0.01
Left Side	16	5	112.8	<0.01
Left Side	18	5	112.8	<0.01

Position	Distance (cm)	Tx Power (W)	Freq (kHz)	H-field (A/m)
Back Side	0	7.5	112.8	3.081
Back Side	2	7.5	112.8	1.161
Back Side	4	7.5	112.8	0.684
Back Side	6	7.5	112.8	0.385
Back Side	8	7.5	112.8	0.257
Back Side	10	7.5	112.8	<0.01
Back Side	12	7.5	112.8	<0.01
Back Side	14	7.5	112.8	<0.01
Back Side	16	7.5	112.8	<0.01
Back Side	18	7.5	112.8	<0.01
Front Side	0	7.5	112.8	2.895
Front Side	2	7.5	112.8	1.206
Front Side	4	7.5	112.8	0.714
Front Side	6	7.5	112.8	0.414
Front Side	8	7.5	112.8	0.280
Front Side	10	7.5	112.8	<0.01
Front Side	12	7.5	112.8	<0.01
Front Side	14	7.5	112.8	<0.01
Front Side	16	7.5	112.8	<0.01
Front Side	18	7.5	112.8	<0.01
Left Side	0	7.5	112.8	4.045
Left Side	2	7.5	112.8	1.534
Left Side	4	7.5	112.8	0.814
Left Side	6	7.5	112.8	0.573
Left Side	8	7.5	112.8	0.243
Left Side	10	7.5	112.8	<0.01
Left Side	12	7.5	112.8	<0.01
Left Side	14	7.5	112.8	<0.01
Left Side	16	7.5	112.8	<0.01
Left Side	18	7.5	112.8	<0.01
Right Side	0	7.5	112.8	3.912
Right Side	2	7.5	112.8	1.560
Right Side	4	7.5	112.8	0.712
Right Side	6	7.5	112.8	0.526
Right Side	8	7.5	112.8	0.356
Right Side	10	7.5	112.8	0.225
Right Side	12	7.5	112.8	<0.01
Right Side	14	7.5	112.8	<0.01
Right Side	16	7.5	112.8	<0.01
Right Side	18	7.5	112.8	<0.01

ANNEX A H-field and SAR Simulation Results

Refer to WPT SAR Simulation report

ANNEX B Accreditation Certificate

United States Department of Commerce
National Institute of Standards and Technology

Certificate of Accreditation to ISO/IEC 17025:2017

NVLAP LAB CODE: 600118-0

Telecommunication Technology Labs, CAICT
Beijing
China

*is accredited by the National Voluntary Laboratory Accreditation Program for specific services,
listed on the Scope of Accreditation, for:*

Electromagnetic Compatibility & Telecommunications

*This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality
management system (refer to joint ISO-ILAC-IAF Communique dated January 2009).*

2022-10-01 through 2023-09-30
Effective Dates




For the National Voluntary Laboratory Accreditation Program